PAT-NO: JP407226485A

DOCUMENT-IDENTIFIER: JP 07226485 A

TITLE: MANUFACTURING METHOD OF CAPACITOR

FOR INTEGRATED CIRCUIT

PUBN-DATE: August 22, 1995

INVENTOR-INFORMATION:

NAME

HIROSE, TATSUYA

ASSIGNEE-INFORMATION:

NAME COUNTRY FUJITSU LTD N/A

APPL-NO: JP06016029

APPL-DATE: February 10, 1994

INT-CL (IPC): H01L027/04, H01L021/822

## ABSTRACT:

PURPOSE: To enable a large <u>capacitor</u> in thin film to be manufactured at low temperature for realizing the on chip **capacitor**.

CONSTITUTION: A lower electrode 13 comprising  $\underline{\mathtt{Ti}}$  is formed on a protective

film 12 comprising SiON covering a substrate 11 and then a high dielectric film

14 comprising <u>TiO</u><SB>2</SB> required of high temperature baking step is formed

at a low temperature having conductivity, next, the surface of the high

dielectric film 14 is heated at a baking temperature by irradiating with the

beams from a heavy hydrogen lamp having the wavelength in a region in shorter

08/28/2003, EAST Version: 1.04.0000

intrusion length than the film thickness of the high did dielectric film 14 and low transmittivity to the film 14 i.e., 125 (nm) and 160 (nm) so as to form extremely thin high resistant film 14A. Next, the high resistant film 14A is used as a substantial dielectric film of a capacitor thereby enabling compact and large capacity capacitor to be manufactured at low temperature.

COPYRIGHT: (C) 1995, JPO